

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/733,845	ANDREWS ET AL.	
Examiner			Art Unit	Evan Pert	
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	B	US-6,211,488	04-2001	Hoekstra et al.	219/121.72
	C	US-5,543,365	08-1996	Wills et al.	438/462
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.